Single-crystal epitaxial thin films of SrFeO₂ with FeO₂ "infinite layers"

Satoru Inoue,¹ Masanori Kawai,¹ Yuichi Shimakawa,^{1,a)} Masaichiro Mizumaki,² Naomi Kawamura,² Takashi Watanabe,³ Yoshihiro Tsujimoto,³ Hiroshi Kageyama,³ and Kazuyoshi Yoshimura³

¹Institute for Chemical Research, Kyoto University, Uji, Kyoto 611-0011, Japan

²Japan Synchrotron Radiation Research Institute/SPring-8, Sayo, Hyogo 679-5198, Japan

³Department of Chemistry, Graduate School of Science, Kyoto University, Sakyo, Kyoto 606-8502, Japan

(Received 22 February 2008; accepted 2 April 2008; published online 25 April 2008)

Single-crystal thin films of SrFeO₂, which is an oxygen-deficient perovskite with "infinite layers" of Fe²⁺O₂, were prepared by using CaH₂ for low-temperature reduction of epitaxial SrFeO_{2.5} single-crystal films deposited on KTaO₃ substrates. This reduction process, removing oxygen ions from the perovskite structure framework and causing rearrangements of oxygen ions, topotactically transforms the brownmillerite SrFeO_{2.5} to the *c*-axis oriented SrFeO₂. © 2008 American Institute of *Physics*. [DOI: 10.1063/1.2913164]

Strontium and iron form a number of oxygen-deficient perovskite structure oxides: SrFeO_{3- δ} with δ ranging from 0 to 0.5.¹ SrFeO₃ (δ =0) with Fe⁴⁺O₆ octahedra has been synthesized in bulk form at 400-550 °C under an oxygen partial pressure of 10⁵ Torr (Ref. 2) and has also been prepared in a thin film form by pulsed laser deposition (PLD) following *in situ* oxidization with flowing O_3 .^{3,4} This strongly oxidizing atmosphere stabilized the unusually high ionic state of Fe⁴⁺. SrFeO_{2.5} (δ =0.5), on the other hand, has been prepared at ambient pressure and its brownmillerite structure consists of alternate layers of Fe³⁺O₆ octahedra and Fe³⁺O₄ tetrahedra [Fig. 1(a)]. However, it was not possible to produce SrFeO₂ (δ =1.0), a perovskite with Fe²⁺ ions, by using H₂/Ar gas or electrochemical reduction techniques⁵ because the perovskite structure was not conserved under those reducing conditions in thermodynamically controlled solid-state reaction processes.6

SrFeO₂ was recently synthesized by reducing SrFeO_{2.875} (Sr₈Fe₈O₂₃) with CaH₂ at 280 °C,⁷ a temperature too low for structural rearrangement but high enough that the oxygen ions could change their positions. SrFeO₂ is an oxygen-deficient perovskite and is isostructural with the "infinite-layer" cupric oxides used to make high- T_C superconductors.⁸ Its crystal structure [Fig. 1(b)] consists of FeO₂ planes with corner-sharing square-planar coordinated FeO₄ and at room temperature, its tetragonal (*P*4/*mmm*) lattice constants are *a*=3.991 and *c*=3.474 Å. The lack of apical oxygen in SrFeO₂ makes its crystal structure highly anisotropic and makes its magnetism two dimensional, and the high mobility of the oxygen ions in SrFeO₂ would make it a useful material for the electrodes in solid-oxide fuel cells and batteries.⁹

Square-planar oxygen coordination around Fe^{2+} is extremely rare because iron ions are favorably tetrahedrally or octahedrally coordinated by oxygen irons. To understand the crystallographic, electronic, and magnetic characteristics of SrFeO₂, we need to investigate them in studies with single-crystal samples. In this letter, we report the crystal structure and the ionic state of Fe in single-crystal epitaxial thin films of SrFeO₂ prepared by *ex situ* reduction of epitaxially grown brownmillerite SrFeO_{2.5} films.

The SrFeO_{2.5} precursor ceramic target was first prepared in a solid-state reaction under an oxygen partial pressure of 10⁻⁴ Torr. The SrFeO_{2.5} precursor was deposited on a KTaO₃ substrate by PLD using a KrF excimer laser pulse with an energy density of 0.4 J/cm². KTaO₃ single-crystal substrates were used in this study because the cubic lattice constant of KTaO₃, 3.988 Å, is quite close to the *a* lattice constant of SrFeO₂. The obtained SrFeO_{2.5} film samples were treated in a way similar to that in which the bulk samples described in Ref. 7 were treated. The bulk samples were treated with CaH₂ in a mixed compressed disk, whereas each of the present 5 mm square SrFeO_{2.5} film samples was embedded with about 0.2 g of CaH₂ in an evacuated Pyrex tube in an Ar-filled glove box. The tube was sealed in vacuum and then kept at 280 °C for 24 h. The residual products, including CaH₂, on the film surface were removed by washing with 2-butanone. The crystal structure of the resultant material was examined by $2\theta - \theta$ x-ray diffraction (XRD) measurement with Cu $K\alpha$ radiation. The XRD intensity map in (H,L) reciprocal lattice space was also measured with a



FIG. 1. (Color online) (a) SrFeO_{2.5} brownmillerite structure consisting of alternate layers of FeO₆ octahedra and FeO₄ tetrahedra. (b) SrFeO₂ infinite-layer structure consisting of corner-sharing planar FeO₄ and Sr. Note that the *b* axis of SrFeO_{2.5} and the *c* axis of SrFeO₂ are perpendicular to the film plane.

92, 161911-1

Downloaded 27 Apr 2008 to 130.54.110.22. Redistribution subject to AIP license or copyright; see http://apl.aip.org/apl/copyright.jsp

^{a)}Electronic mail: shimak@scl.kyoto-u.ac.jp.

^{© 2008} American Institute of Physics



FIG. 2. (Color online) XRD patterns of (a) $SrFeO_{2.5}$ target (linear scale), (b) $SrFeO_{2.5}$ film grown on $KTaO_3$ (logarithmic scale), and (c) reduced $SrFeO_2$ film (logarithmic scale).

four-circle diffractometer. Here, the reciprocal-space coordinates correspond to those of the cubic KTaO₃ substrate, and thus, H=1.0 and L=1.0 correspond to 1/a (KTaO₃) = 1/3.988 Å⁻¹. The x-ray absorption spectra (XAS) near the Fe *K* edge were examined at the BL39XU beamline of SPring-8 in order to see the change in Fe oxidation state. They were recorded at room temperature with a fluorescence mode.

The SrFeO_{2.5} precursor ceramic was confirmed to have the brownmillerite structure by powder XRD [Fig. 2(a)]. The deposition with the SrFeO_{2.5} precursor target under an oxygen pressure of 10⁻⁵ Torr at 700 °C yielded *b*-axis oriented epitaxial SrFeO_{2.5} thin films. X-ray reflectivity revealed that the films deposited were typically 170-200 Å thick. In the $2\theta - \theta$ XRD pattern shown in Fig. 2(b), one sees the (0 0 l) reflections of the perovskite structure and the $(0 \ 0 \ l/2)$ twofold superstructure reflections due to the ordering of the oxygen defects in the SrFeO_{2.5} brownmillerite structure. Note here that the indices are based on the primitive cubic perovskite cell $(a \sim 3.9 \text{ Å})$ and the original b axis of the brownmillerite structure (the stacking direction of the layered structure) is converted to the c axis. An XRD logarithmic intensity map in the reciprocal lattice space around the (1 0 3) Bragg reflection of the $KTaO_3$ perovskite structure is shown in Fig. 3(a), where both the KTaO₃ Bragg reflection at (H,L) = (1.00, 3.00) and a diffraction peak from the film at $(H,L) \approx (1.00, 3.08)$ are evident. Since the peak positions along the H and L directions give information on the in-plane and out-of-plane lattices, respectively, the data indicate that the in-plane lattice constant of the SrFeO_{2.5} film is comparable to the KTaO3 cubic lattice and that the out-of-plane lattice constant of the film is smaller than that of the KTaO₃



FIG. 3. (Color online) Logarithmic x-ray intensity reciprocal space maps around the (1 0 3) Bragg reflection of (a) $SrFeO_{2.5}$ and (b) the $SrFeO_2$ thin films.

substrate. Therefore, these XRD results clearly show that the growth of the pseudo-tetragonal brownmillerite $SrFeO_{2.5}$ film on the KTaO₃ substrate was epitaxial.

A 2θ - θ XRD pattern of the CaH₂-treated film is shown in Fig. 2(c). None of the diffraction peaks originating from SrFeO_{2.5} are evident but the peaks corresponding to d=1.75 and 0.87 Å ($2\theta \approx 52^{\circ}$ and 123°, respectively) are evident. The positions of these peaks are close to those of the $(0 \ 0 \ 2)$ and $(0 \ 0 \ 4)$ reflections of the bulk SrFeO₂. The intensities for the infinite-layer SrFeO₂ structure that were calculated by the XRD intensity simulation program RIETAN-2000, I_{002} : I_{003} : I_{004} = 10 361: 29: 1874 =1.0:0.0028:0.18, agree well with the observed intensities: $I_{002}: I_{003}: I_{004} \approx 1:0:0.14$. Figure 3(b) shows a reciprocal lattice map of the reduced thin film sample. In addition to the $(1 \ 0 \ 3)$ Bragg reflection of the cubic KTaO₃ substrate, there is a peak at $(H,L) \approx (1.00, 3.42)$. The lattice constants obtained from the diffraction data were a=3.988 and c=3.493 Å, which are consistent with those reported for powder samples of SrFeO₂.

XAS spectra near the Fe K edge are shown in Fig. 4 for the SrFeO_{2.5} precursor and CaH₂-treated thin film samples. The difference in the shape of their XAS spectra is due to the changes in the electronic states and local structure of Fe ions.¹⁰ The Fe K absorption edge energy of the reduced thin film was about 1.5 eV lower than that of the SrFeO_{2.5} precursor thin film. This chemical shift indicates that the Fe oxidation state in the CaH2-treated thin film sample was reduced to that close to Fe²⁺, and all of the XRD and XAS results indicate that the epitaxial SrFeO_{2.5} thin film was reduced to one of $SrFeO_2$. We can therefore conclude that the reduced thin film obtained is single-crystal SrFeO₂ with the infinite-layer structure. The pre-edge structures shown in the inset of Fig. 4 have never been observed in any iron oxides, and thus, they appear to originate from the characteristic square-planar coordination of Fe²⁺ ions. The details of the analysis will be published elsewhere.¹¹

nd out-of-plane lattices, respectively, the data indicate that ne in-plane lattice constant of the $SrFeO_{2.5}$ film is compaable to the $KTaO_3$ cubic lattice and that the out-of-plane attice constant of the film is smaller than that of the $KTaO_3$ Downloaded 27 Apr 2008 to 130.54.110.22. Redistribution subject to AIP license or copyright; see http://apl.aip.org/apl/copyright.jsp



FIG. 4. (Color online) X-ray absorption spectra near the Fe K edge of (a) SrFeO_{2.5} and (b) SrFeO₂ thin films. The inset shows the pre-edge spectrum of SrFeO₂.

film to topotactically change into the *c*-axis oriented $SrFeO_2$ infinite-ayer single crystal, which has an out-of-plane lattice constant of 9.8% smaller than that of $SrFeO_{2.5}$ but has almost the same in-plane lattice structure. In the single-crystal thin film sample, the crystal lattice is under strain due to the lattice mismatch to the substrate $KTaO_3$ lattice. Indeed, the in-plane *a* lattice constant of the single-crystal $SrFeO_2$ (3.988 Å) is slightly smaller than that of bulk $SrFeO_2$ (3.991 Å). As a result, the observed out-of-plane lattice constant of the single-crystal $SrFeO_2$ (3.493 Å) is a bit larger than that of the bulk material (3.474 Å). This strain should play an important role in the conversion of single-crystal $SrFeO_{2.5}$ to single-crystal $SrFeO_2$. In conclusion, we prepared single-crystal SrFeO₂ thin films by low-temperature reduction of single-crystal SrFeO_{2.5} with CaH₂. XRD and XAS results show that the obtained SrFeO₂ sample is an oxygen-deficient perovskite with infinite layers of Fe²⁺O₂. The present results demonstrate that this low-temperature reduction process and the lattice strain of the thin film remove some oxygen ions from the perovskite structure and rearrange the others, leading to the topotactic change from SrFeO_{2.5} to SrFeO₂.

The synchrotron radiation experiments (Proposal No. 2007A2061) were performed with the approval of the Japan Synchrotron Radiation Research Institute. This work was partly supported by the Grants-in-Aid for Scientific Research (Grants Nos. 19GS0207, 18350097, 18655076, 19052004, and 16076210) and by the Joint Project of Chemical Synthesis Core Research Institutions from the Ministry of Education, Culture, Sports, Science and Technology, (MEXT) of Japan.

- ¹J. P. Hodges, S. Short, J. D. Jorgensen, X. Xiong, B. Dabrowski, S. M. Mini, and C. W. Kimball, J. Solid State Chem. **151**, 190 (2000).
- ²J. B. MacChesney, R. C. Sherwood, and J. F. Potter, J. Chem. Phys. **43**, 1907 (1965).
- ³N. Hayashi, T. Terashima, and M. Takano, J. Mater. Chem. **11**, 2235 (2001).
- ⁴H. Yamada, M. Kawasaki, and Y. Tokura, Appl. Phys. Lett. **80**, 622 (2002).
- ⁵J. C. Grenier, A. Wattiaux, J. P. Doumerc, P. Dordor, L. Fournes, J. P. Chaminade, and M. Pouchard, J. Solid State Chem. **96**, 20 (1992).
- ^bM. A. Hayward and M. J. Rosseinsky, Nature (London) **450**, 960 (2007).
- ⁷Y. Tsujimoto, C. Tassel, N. Hayashi, T. Watanabe, H. Kageyama, K. Yoshimura, M. Takano, M. Ceretti, C. Ritter, and W. Paulus, Nature (London) **450**, 1062 (2007).
- ⁸M. Takano, Y. Takeda, H. Okada, M. Miyamoto, and T. Kusaka, Physica C 159, 375 (1989).
- ⁹A. Atkinson, S. Barnett, R. J. Gorte, J. T. S. Irvine, A. J. Mcevoy, M. Mogensen, S. C. Singhal, and J. Vohs, Nat. Mater. **3**, 17 (2004).
- ¹⁰S. J. Roosendaal, B. van Asselen, J. W. Elsenaar, A. M. Vredenberg, and F. H. P. M. Habraken, Surf. Sci. 442, 329 (1999).
- ¹¹M. Mizumaki (unpublished).